

Today's outline - September 07, 2021



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- Undulator spectrum

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- Undulator spectrum
- Undulator coherence

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- Undulator spectrum
- Undulator coherence
- APS-U, ERLs and FELs

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- APS-U, ERLs and FELs
- Detectors

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Reading Assignment: Chapter 3.1–3.3

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Reading Assignment: Chapter 3.1–3.3

Homework Assignment #02:

Problems on Blackboard

due Tuesday, September 21, 2021

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- Undulator spectrum
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Reading Assignment: Chapter 3.1–3.3

Homework Assignment #02:

Problems on Blackboard

due Tuesday, September 21, 2021

Homework Assignment #03:

Chapter 3: 1,3,4,6,8

due Tuesday, October 05, 2021



For an undulator of period λ_u we have derived the following undulator parameters and their relationships:



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the fundamental wavelength of the undulator, λ_1 and the origin of the odd and even harmonics

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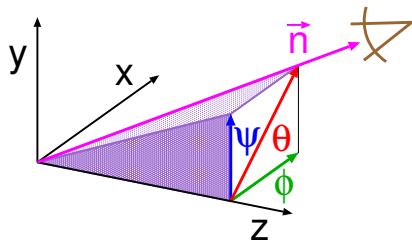
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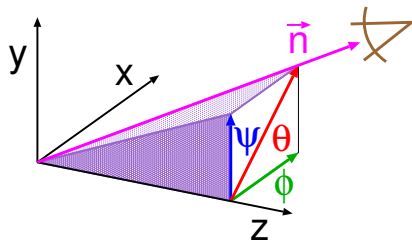
Now let us look at additional properties

Higher harmonics



Recall that we developed an expression for the Doppler time compression of the emission from a moving electron as a function of the observer angle.

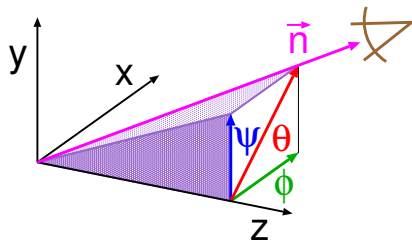
Higher harmonics



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$$\frac{dt}{dt'} = 1 - \vec{n} \cdot \vec{\beta}(t')$$

Higher harmonics

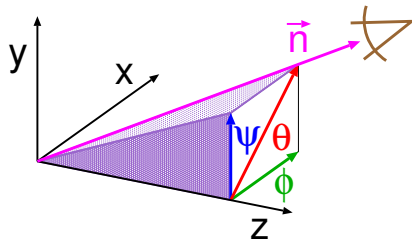


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This can be rewritten in terms of the coordinates in the figure using the vector of unit length in the observer direction:

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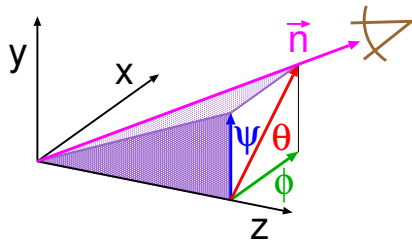
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$$\vec{n} = \left\{ \phi, \psi, \sqrt{1 - \theta^2} \right\}$$

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Higher harmonics



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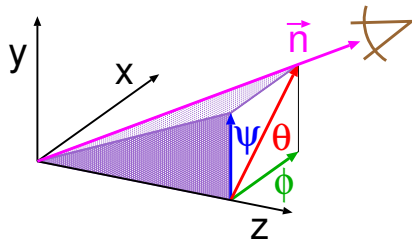
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This can be rewritten in terms of the coordinates in the figure using the vector of unit length in the observer direction:

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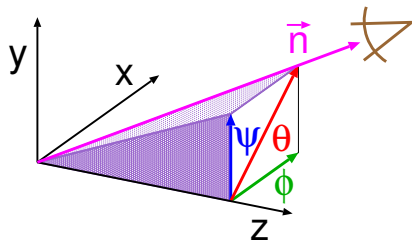
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This differential equation can be solved, realizing that ϕ and θ are constant while $\alpha(t')$ varies as the electron moves through the insertion device, and gives:



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The motion of the electron, $\sin \omega_u t'$, is always sinusoidal, but because of the additional terms, the motion as seen by the observer, $\sin \omega_1 t$, is not.

On-axis undulator characteristics



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On-axis undulator characteristics



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On-axis undulator characteristics



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On-axis undulator characteristics

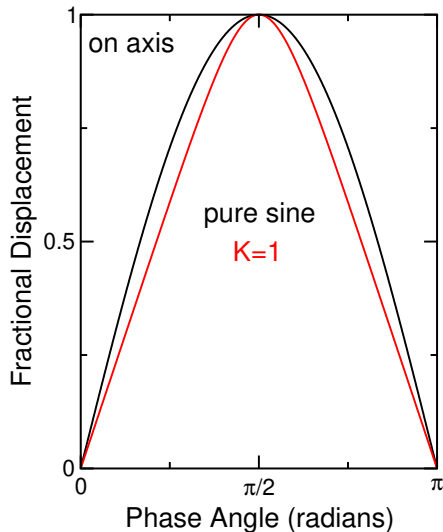


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Plotting $\sin\omega_u t'$ and $\sin\omega_1 t$ shows the deviation from sinusoidal.



On-axis undulator characteristics



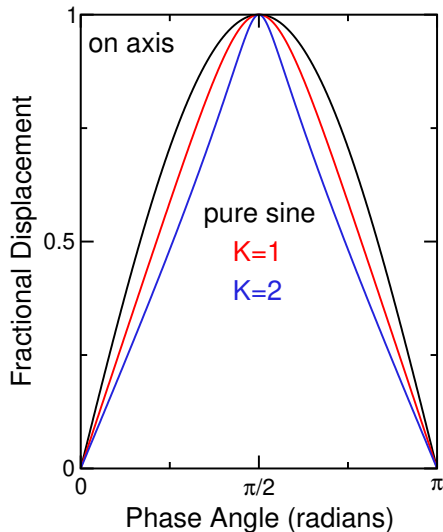
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Similarly, for $K = 2$



On-axis undulator characteristics



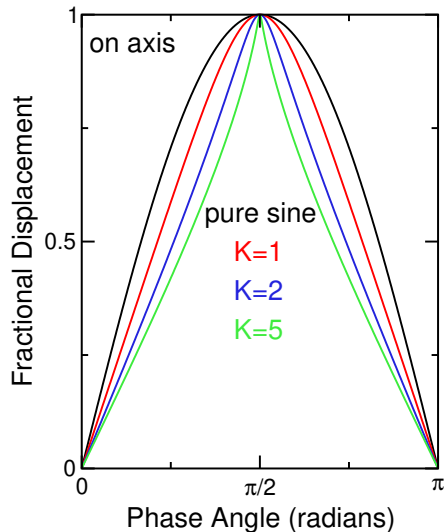
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Similarly, for $K = 2$ and $K = 5$, the deviation becomes more pronounced.



On-axis undulator characteristics



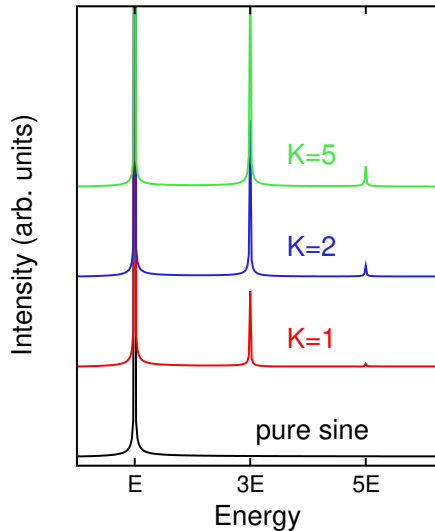
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Similarly, for $K = 2$ and $K = 5$, the deviation becomes more pronounced. This shows how higher harmonics must be present in the radiation as seen by the observer.

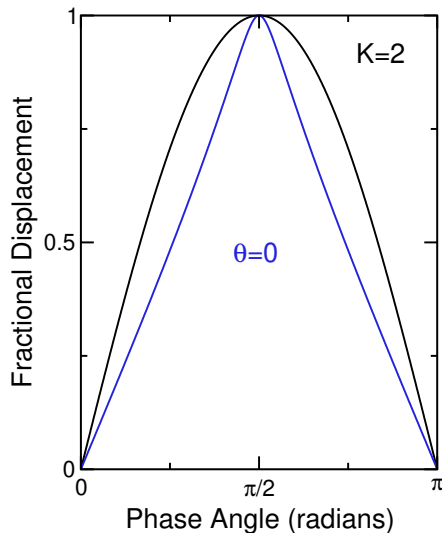


Off-axis undulator characteristics



$$\omega_1 t = \omega_u t' - \frac{K^2/4}{1 + (\gamma\theta)^2 + K^2/2} \sin(2\omega_u t') \\ - \frac{2K\gamma}{1 + (\gamma\theta)^2 + K^2/2} \phi \sin(\omega_u t')$$

When $K = 2$ and $\theta = \phi = 1/\gamma$, we have



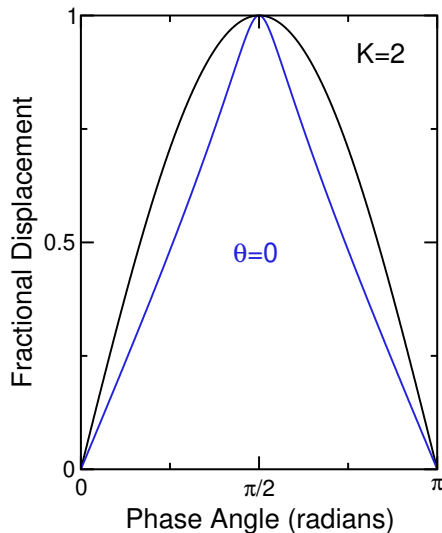
Off-axis undulator characteristics



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Off-axis undulator characteristics

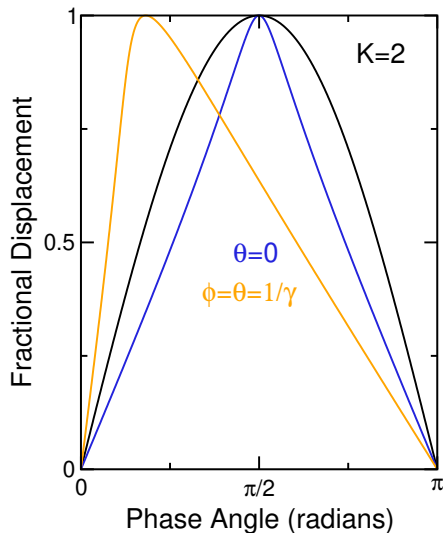


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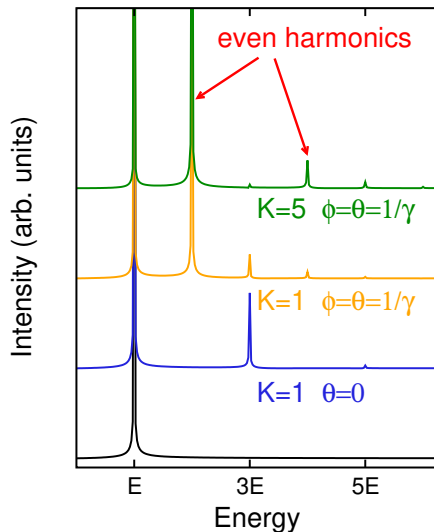


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$$\omega_1 t = \omega_u t' + \frac{1}{4} \sin(2\omega_u t') + \sin \omega_u t'$$

The last term introduces an antisymmetric term which skews the function and leads to the presence of forbidden harmonics (2^{nd} , 4^{th} , etc) in the radiation from the undulator compared to the on-axis radiation.



Diffraction grating

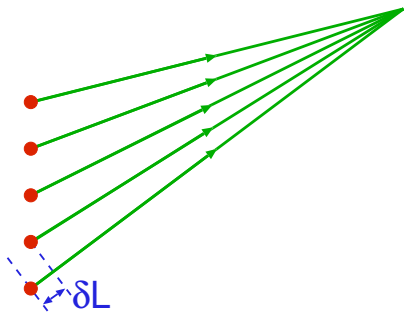


An N period undulator is basically like a diffraction grating, only in the time domain rather than the space domain.

Diffraction grating



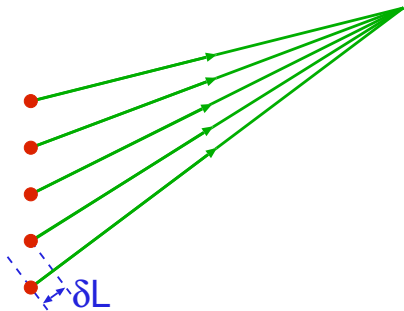
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Diffraction grating



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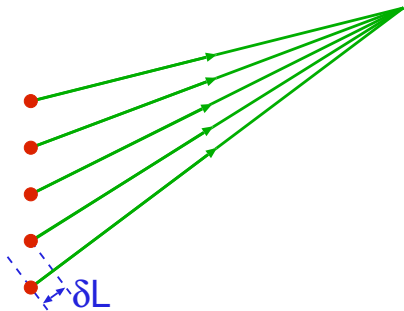


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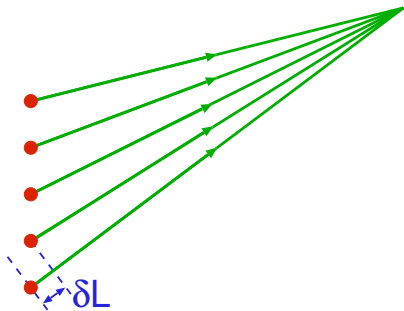


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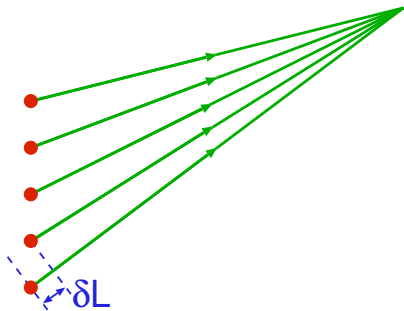


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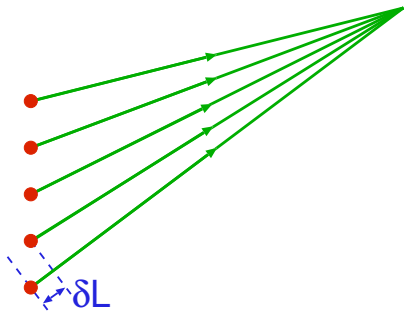
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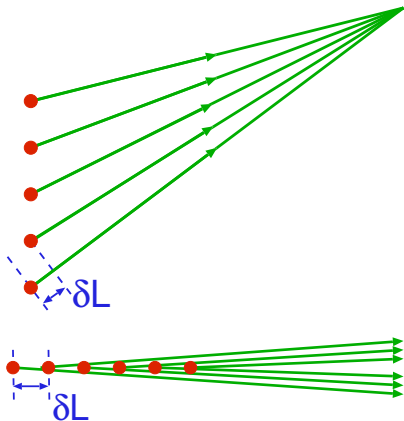
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the phase shift from each undulator pole depends on the wavelength λ_u

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The sum is simply a geometric series, S_N with $k = e^{i2\pi\epsilon}$

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Beam coherence



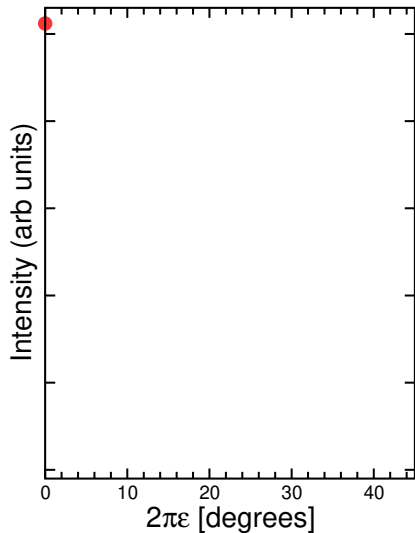
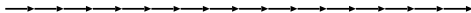
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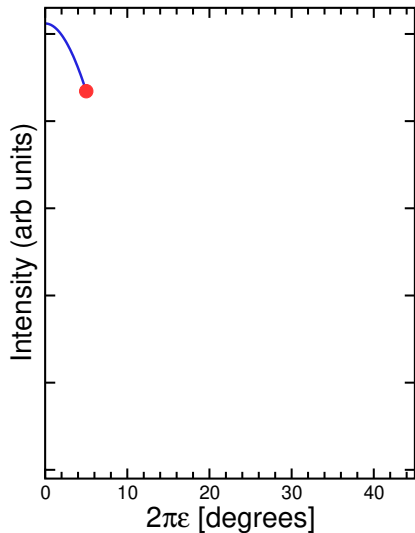
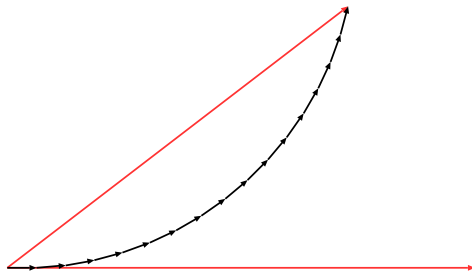


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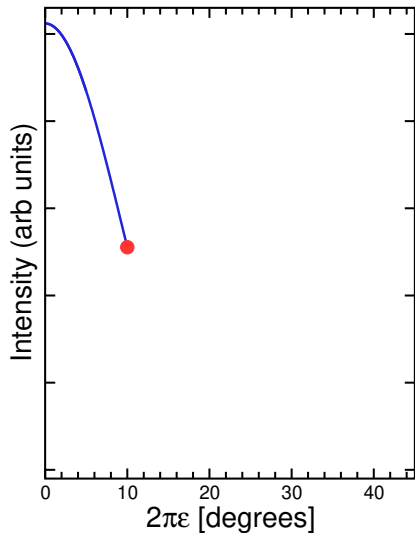
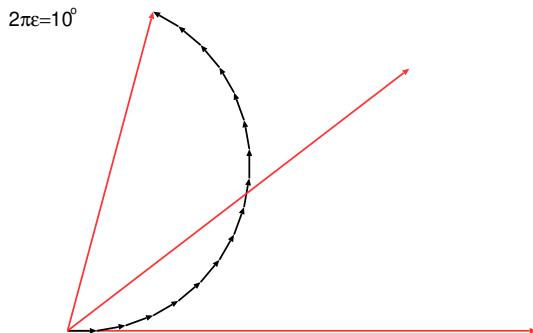
$$2\pi\epsilon = 5^\circ$$



Beam coherence



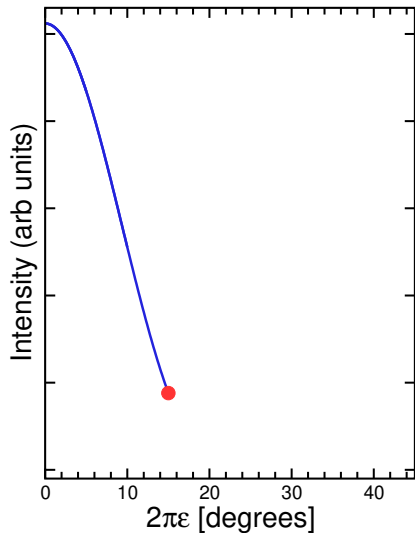
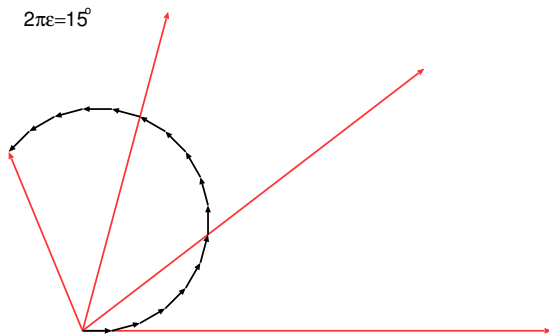
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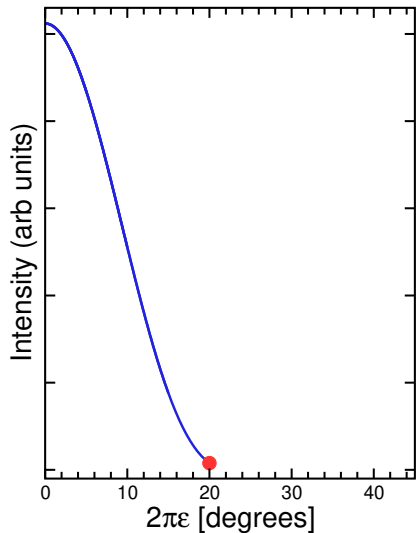
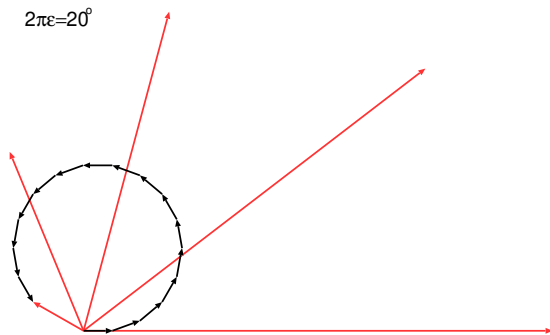
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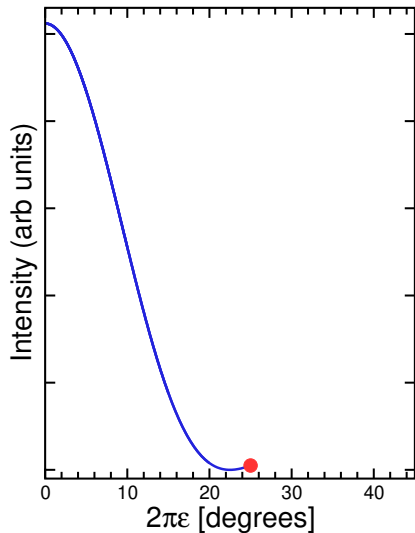
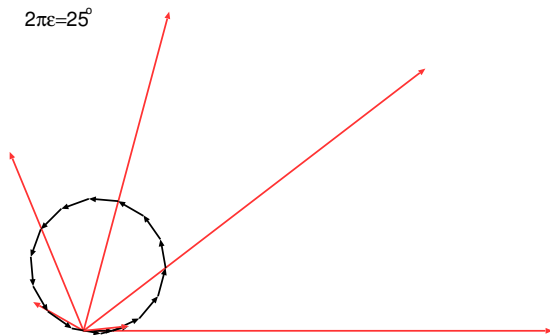
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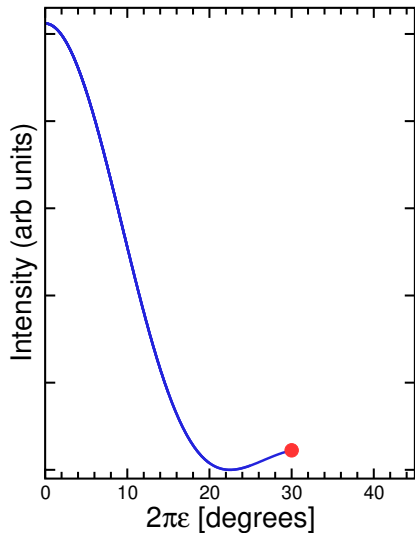
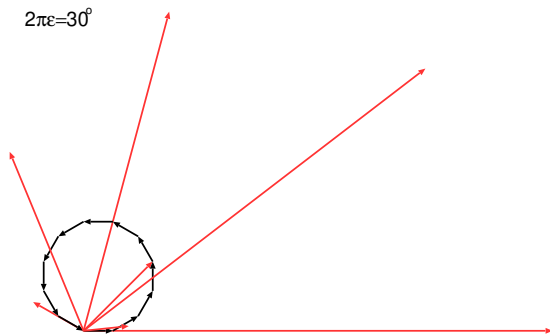
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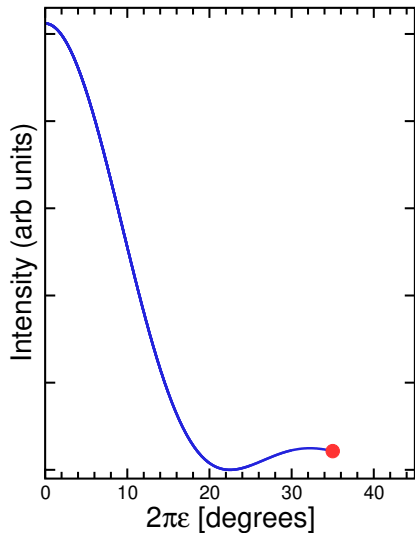
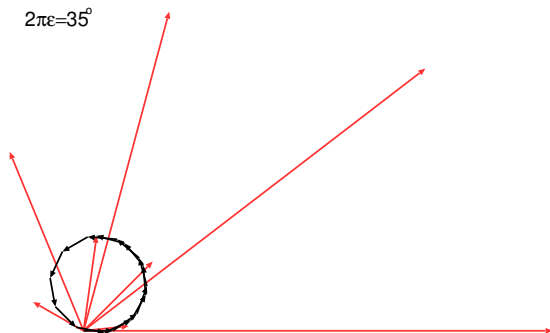
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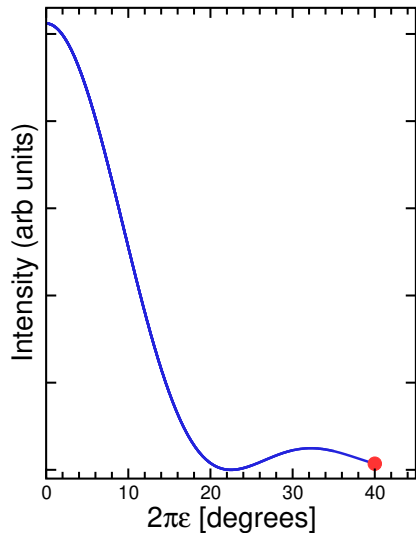
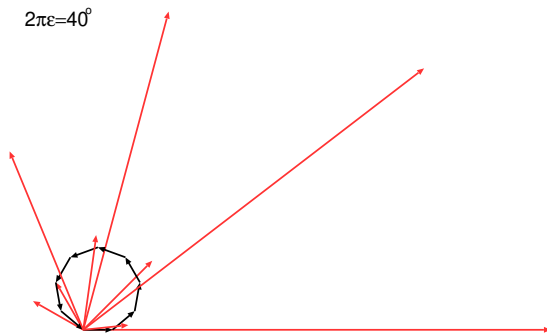
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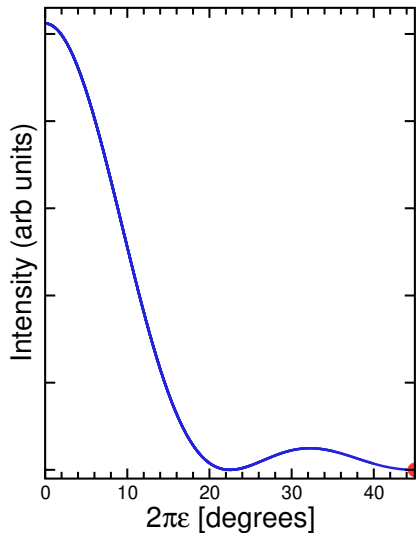
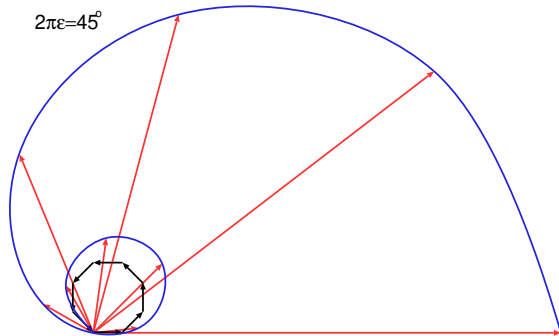
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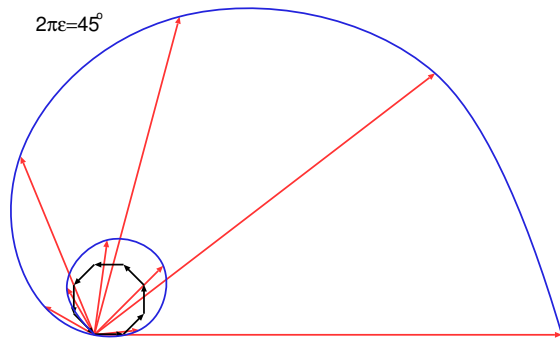
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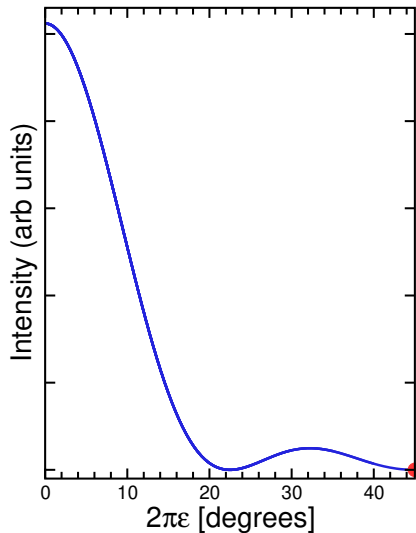
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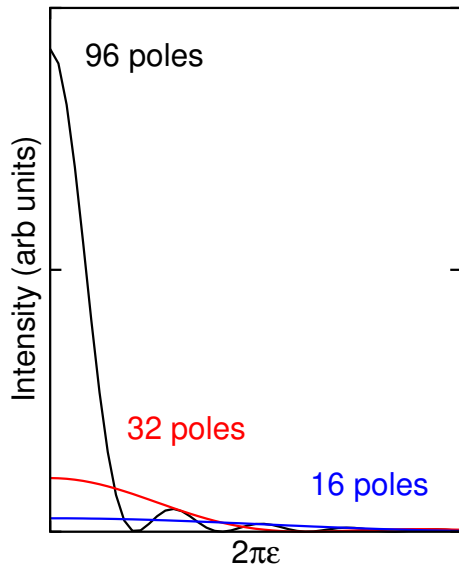
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With the height and width of the peak dependent on the number of poles.

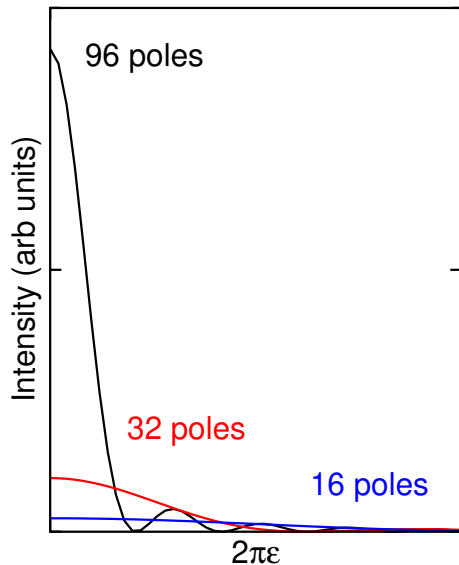


Undulator monochromaticity



The more poles in the undulator, the more monochromatic the beam since a slight change in $\epsilon = \delta L / \lambda$ implies a slightly different wavelength λ

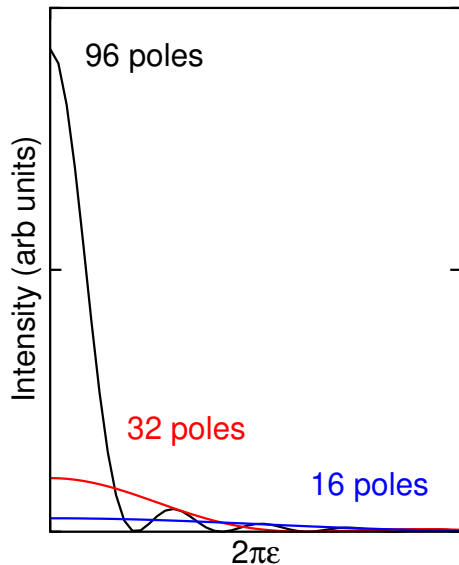
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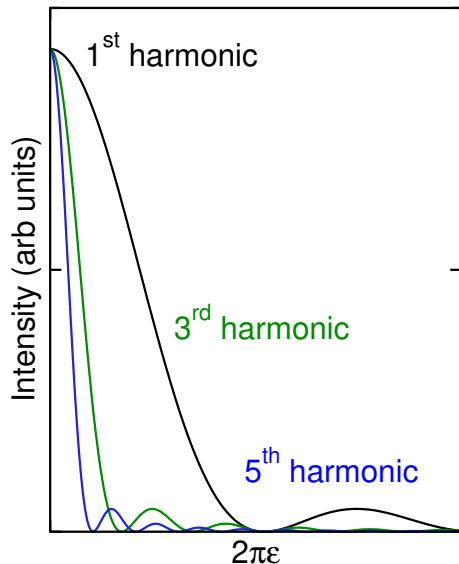


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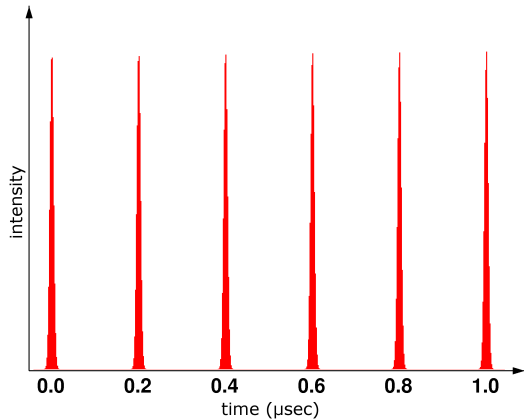
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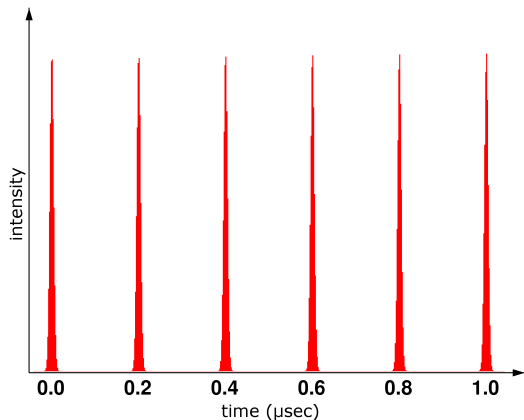
Higher order harmonics have narrower energy bandwidth but lower peak intensity

Synchrotron time structure



There are two important time scales for a storage ring such as the APS: pulse length and interpulse spacing

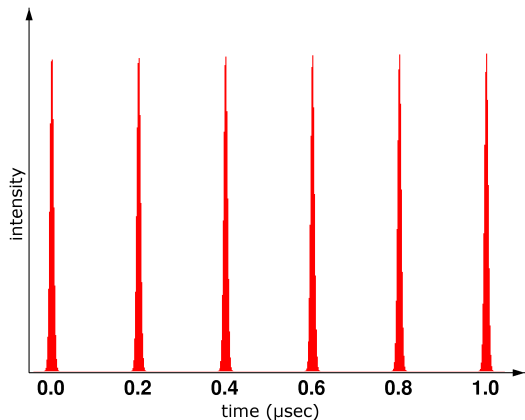
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The APS pulse length in 24-bunch mode is 90 ps while the pulses come every 154 ns

Synchrotron time structure

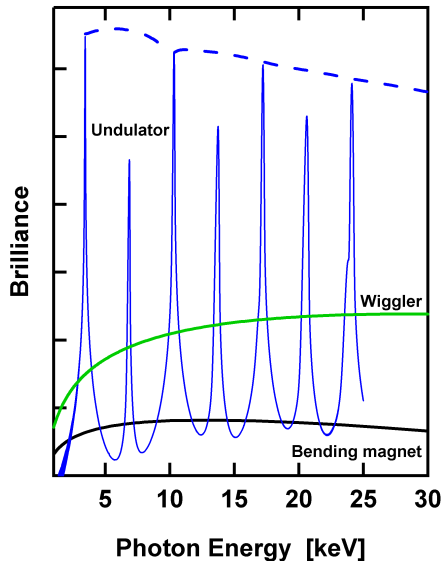


There are two important time scales for a storage ring such as the APS: pulse length and interpulse spacing

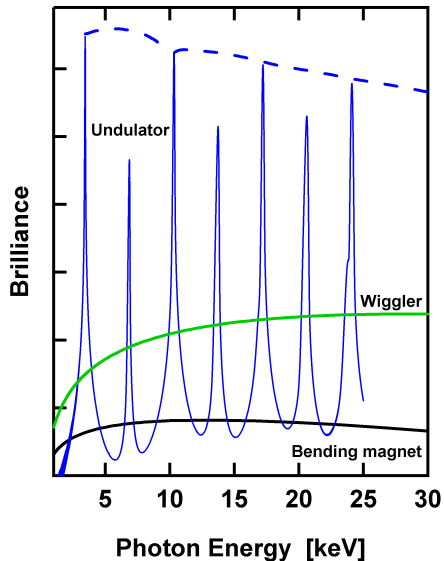
The APS pulse length in 24-bunch mode is 90 ps while the pulses come every 154 ns

Other modes include single-bunch mode for timing experiments and 324-bunch mode (inter pulse timing of 11.7 ns) for a more constant x-ray flux

Spectral comparison

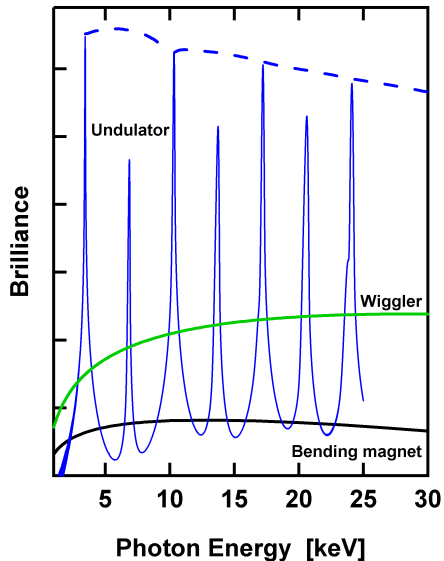


Spectral comparison



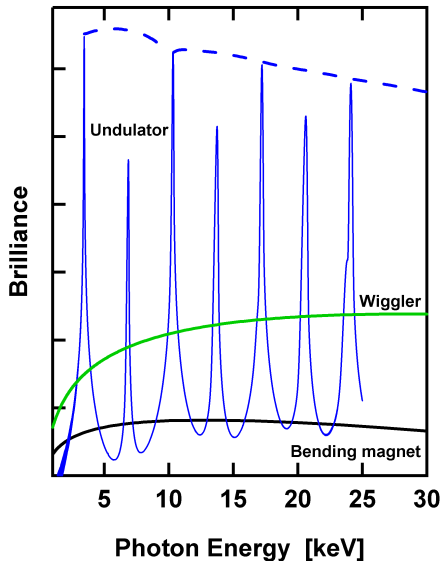
- Bending magnet

Spectral comparison



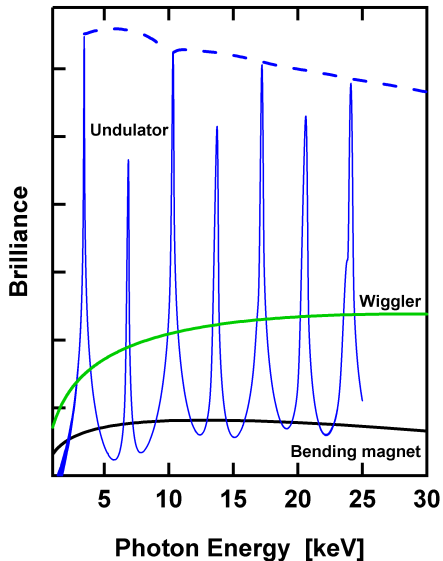
- Bending magnet
 - Broad, nearly white spectrum

Spectral comparison



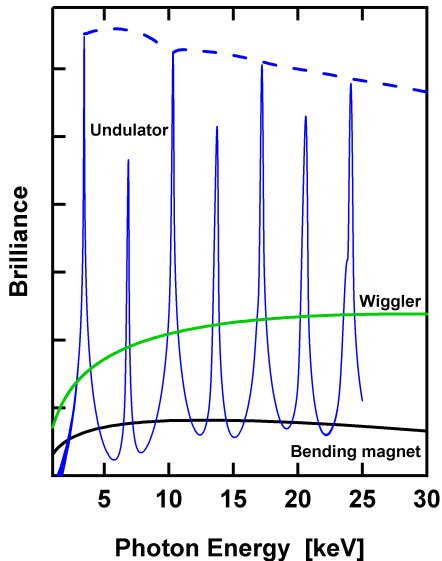
- Bending magnet
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 - Energies extend to 100's of keV

Spectral comparison



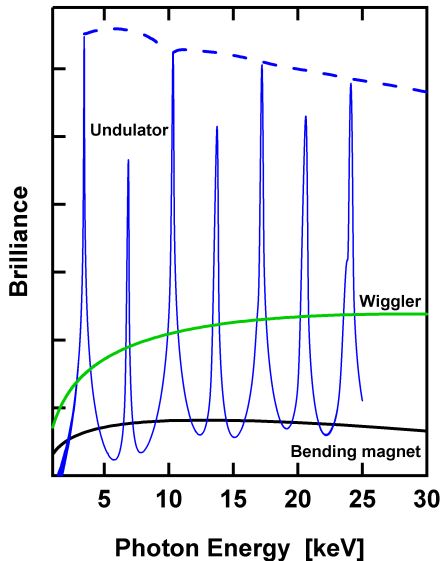
- Bending magnet
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- Wiggler

Spectral comparison



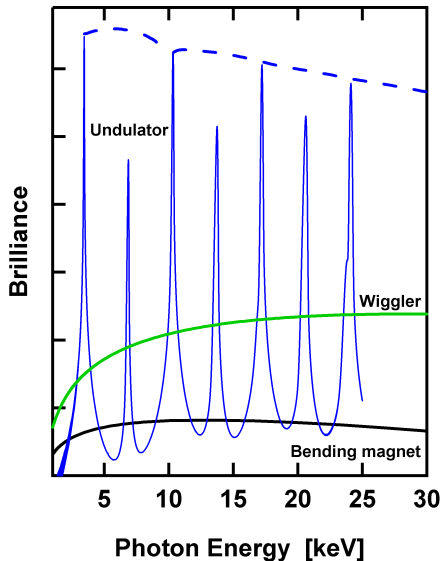
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 - Shifts critical energy higher than bending magnet

Spectral comparison



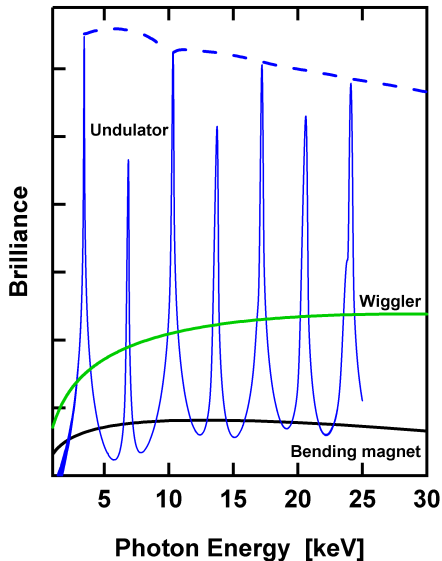
- Bending magnet
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 - Shifts critical energy higher than bending magnet
 - Brilliance is more than an order of magnitude greater than a bending magnet

Spectral comparison



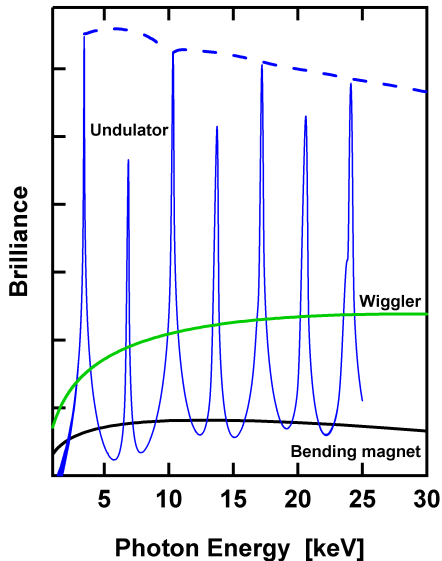
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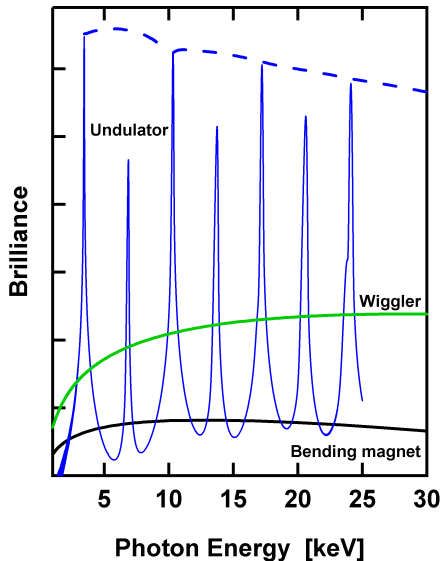
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Spectral comparison



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 - Shifts critical energy higher than bending magnet
 - Brilliance is more than an order of magnitude greater than a bending magnet
- Undulator
 - Brilliance is 6 orders larger than a bending magnet
 - Both odd and even harmonics appear
 - Harmonics can be tuned in energy (dashed lines)



Is there a limit to the brightness of an undulator source at a synchrotron?



Is there a limit to the brightness of an undulator source at a synchrotron?

the brightness is inversely proportional to the square of the product of the linear source size and the angular divergence

$$brightness = \frac{flux \text{ [photons/s]}}{divergence \text{ [mrad}^2\text{]} \cdot source \text{ size [mm}^2\text{]} [0.1\% \text{ bandwidth}]}$$

Emittance

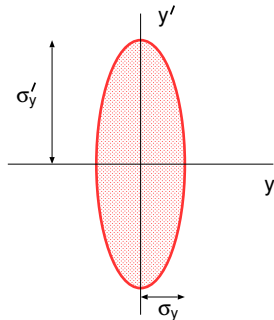


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the product of the source size (σ) and divergence (σ') is called the **emittance**, ϵ



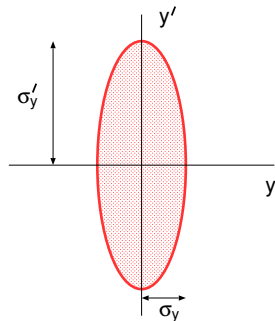


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Emittance



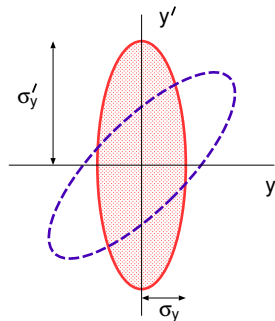
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Emittance



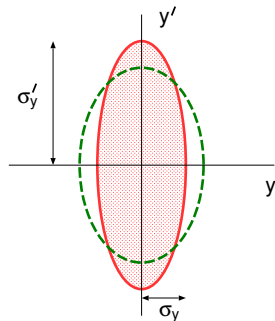
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this **emittance** cannot be changed but it can be **rotated** or **deformed** by magnetic fields as the electron beam travels around the storage ring as long as the area is kept constant



APS emittance



For photon emission from a single electron in
a 2m undulator at $1\text{\AA}$

APS emittance



For photon emission from a single electron in
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$$\sigma_{\gamma} = \frac{\sqrt{L\lambda}}{4\pi} = 1.3\mu\text{m}$$

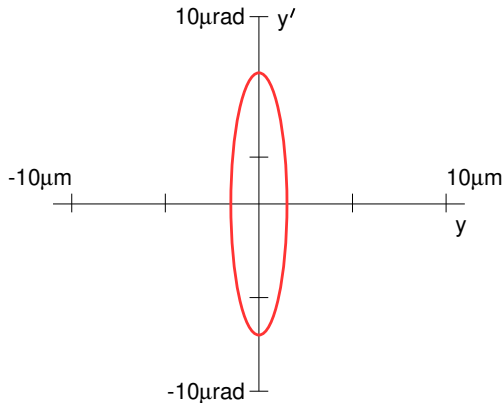
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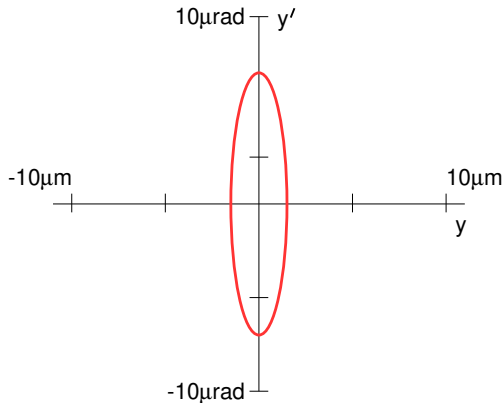


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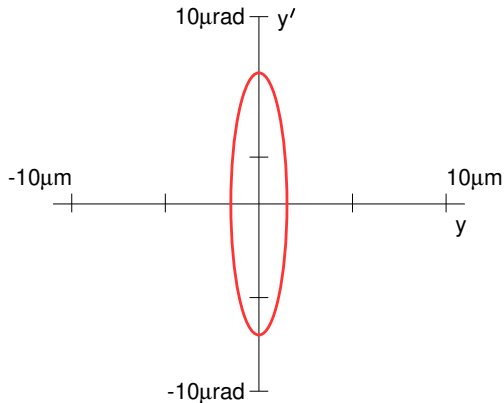
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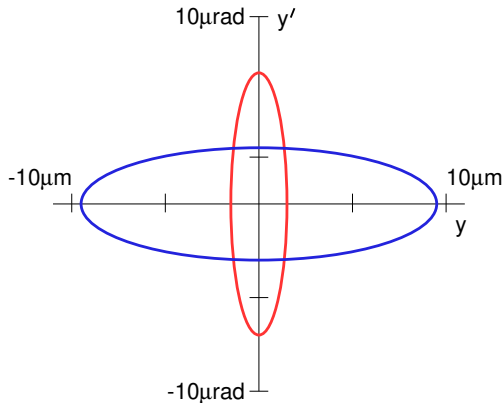
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must convolute to get photon emission from entire beam (in vertical direction)



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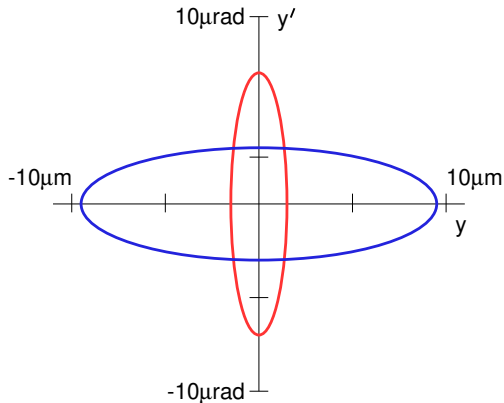
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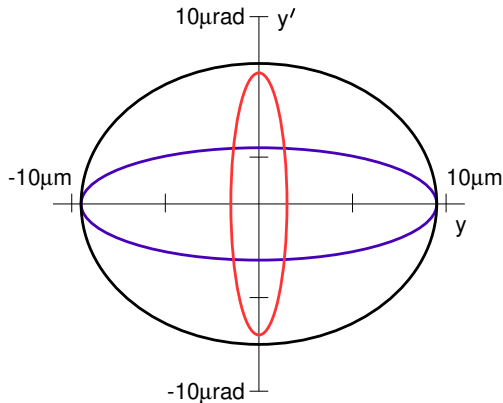
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Evolution of APS parameters



Parameter	1995	APS 2001	2005
Bunches		24 & 324	
σ_x	334 μm	352 μm	280 μm
σ'_x	24 μrad	22 μrad	11.6 μrad
σ_y	89 μm	18.4 μm	9.1 μm
σ'_y	8.9 μrad	4.2 μrad	3.0 μrad

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Evolution of APS parameters



Parameter	APS			APS-U	
	1995	2001	2005	Timing	Brightness
Bunches		24 & 324		48	324
σ_x	334 μm	352 μm	280 μm	18.1 μm	21.8 μm
σ'_x	24 μrad	22 μrad	11.6 μrad	2.6 μrad	3.1 μrad
σ_y	89 μm	18.4 μm	9.1 μm	10.6 μm	4.1 μm
σ'_y	8.9 μrad	4.2 μrad	3.0 μrad	4.2 μrad	1.7 μrad

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The APS-U will make the beam smaller and more square in space making for higher performance insertion device beam lines.

APS upgrade



In 2023, the APS will shut down for a major rebuild with a totally new magnetic lattice.

APS upgrade

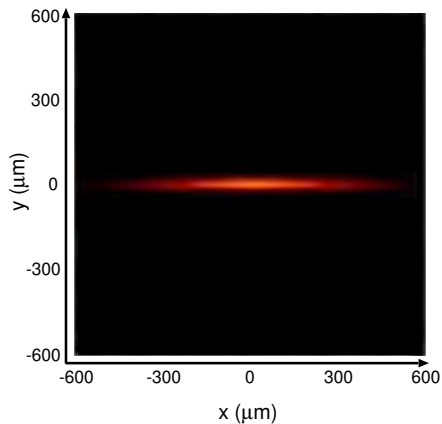


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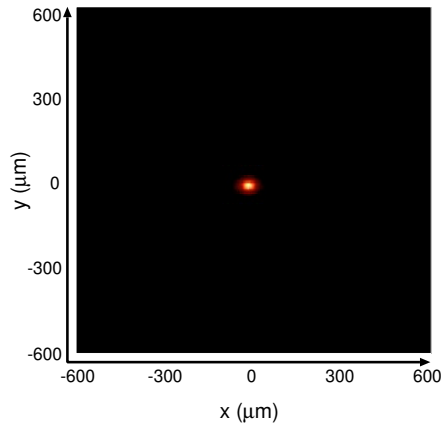
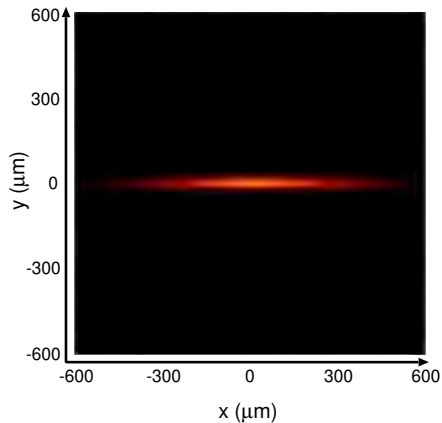
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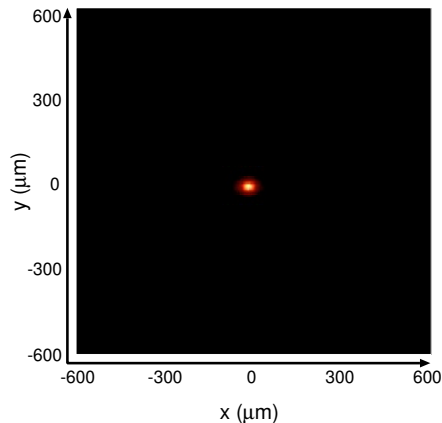
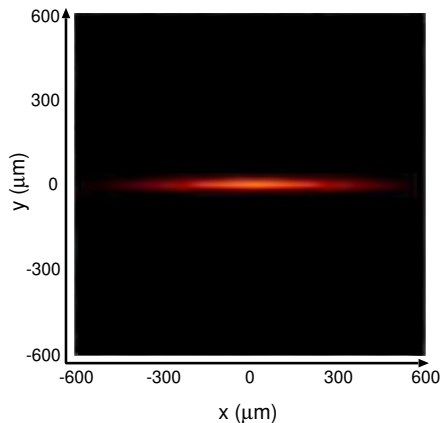
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APS upgrade



In 2023, the APS will shut down for a major rebuild with a totally new magnetic lattice. One of the biggest changes will be the beam (source) size and emittance



The beam will be nearly square and there will be much more coherence from the undulators

APS-U magnet layout



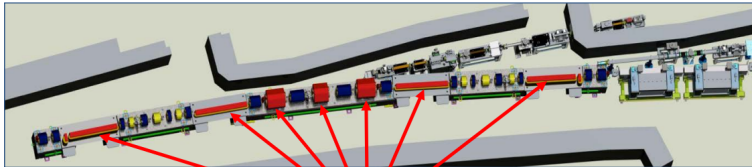
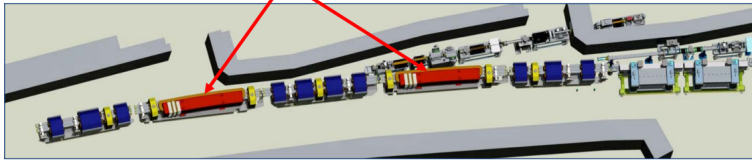
The APS upgrade will install a multi-bend achromat instead of the two bending magnets.

APS-U magnet layout



The APS upgrade will install a multi-bend achromat instead of the two bending magnets.

two dipole magnets – double-bend-achromat



Seven dipole magnets – multi-bend-achromat (MBA)

APSU undulator performance



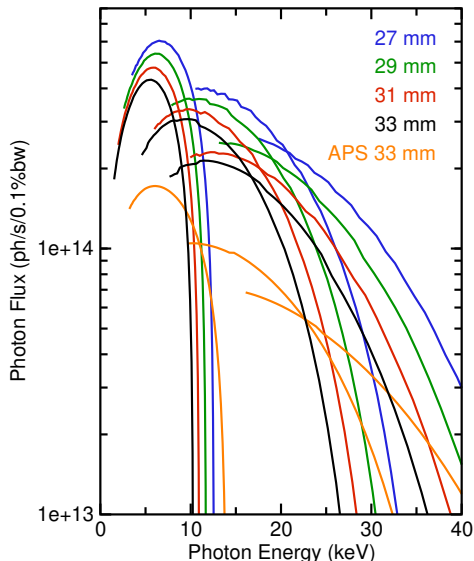
The multi-bend achromat will produce a diffraction-limited source with a lower energy (6.0 GeV) and doubled current (200 mA).

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Since MRCAT's science is primarily flux driven, the goal will be to replace the 2.4m undulator with one that outperforms the current 33mm period but with only modest increase in power.



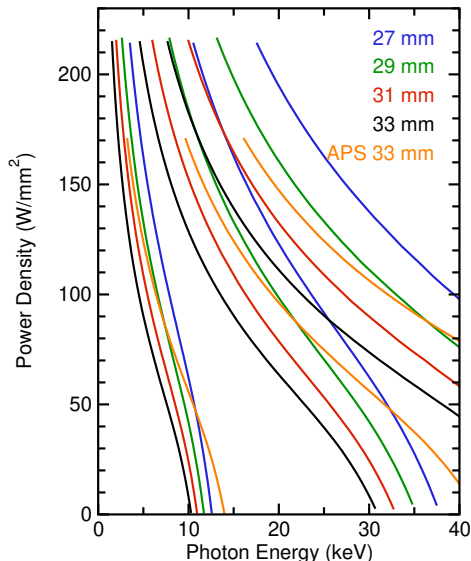
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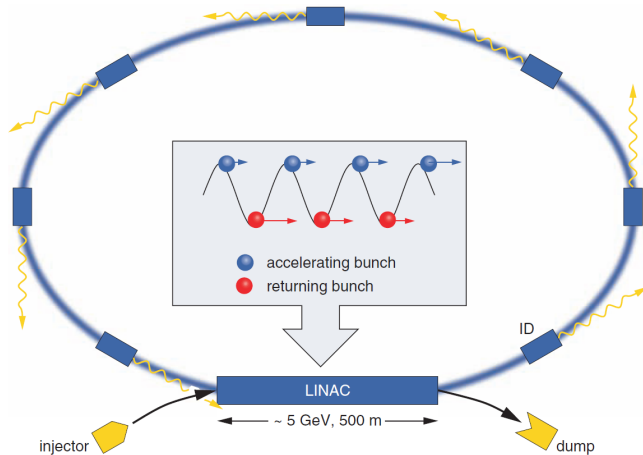
The APS-U is an example of a "4th" generation synchrotron source



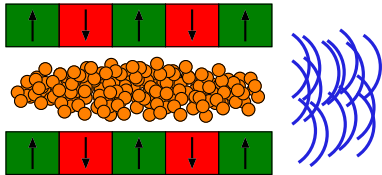
Energy recovery linacs



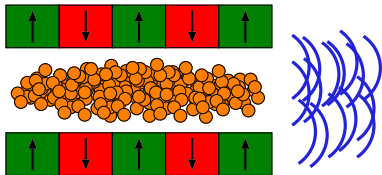
Another way to increase the undulator peak brilliance is the energy recovery linac which overcomes the fundamental limitation of a synchrotron by passing the beam through only once.



Free electron laser

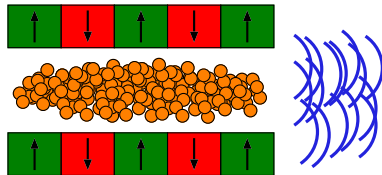


Free electron laser



Initial electron cloud, each electron emits coherently but independently

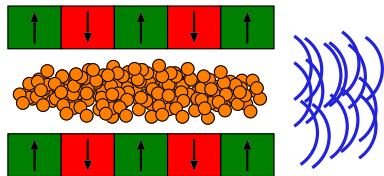
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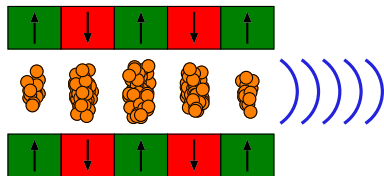
Over course of 100 m, electric field of photons, feeds back on the electron bunch

Free electron laser

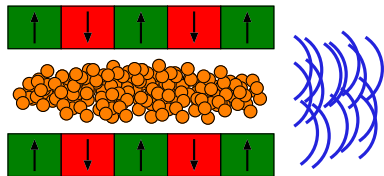


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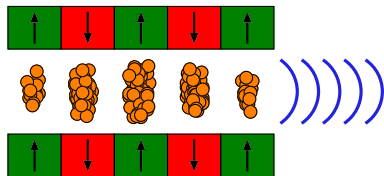


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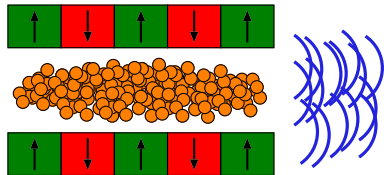
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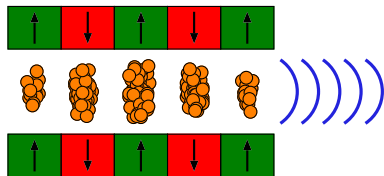
Microbunches form with period of FEL (and radiation in electron frame)

Free electron laser



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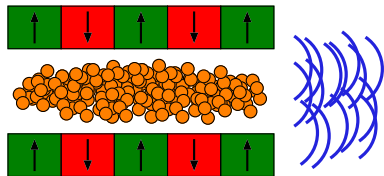
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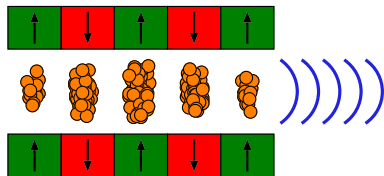
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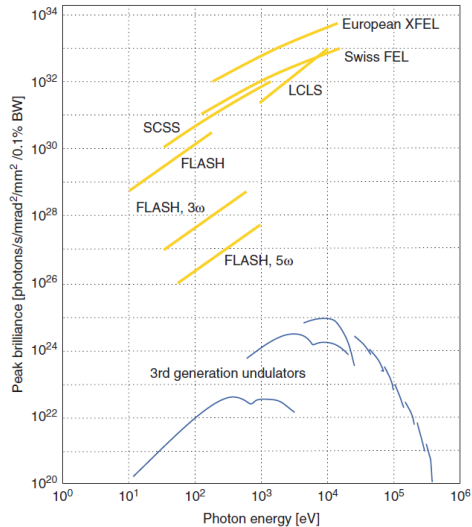
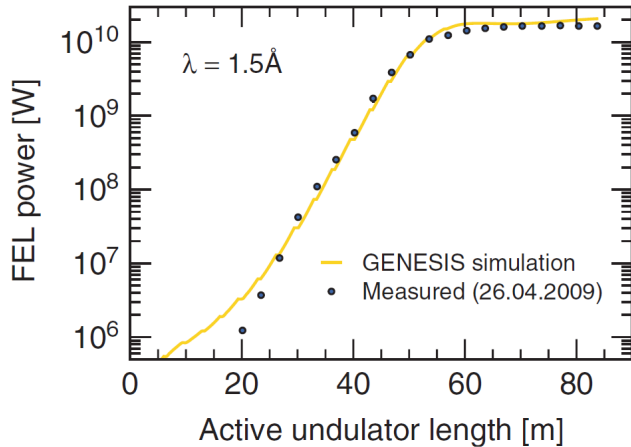


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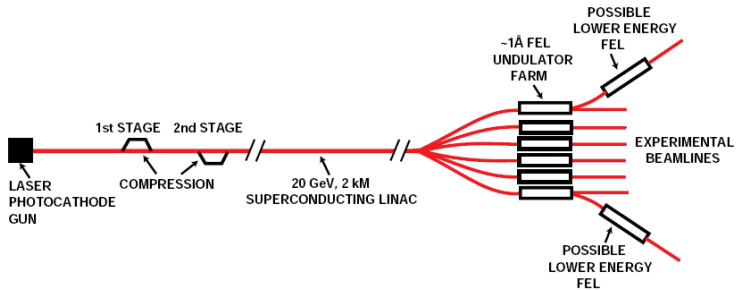
Each microbunch emits coherently with neighboring ones

Again, an alternative way to view this is that the pulse train from a 100m long undulator is long enough in time to produce a monochromatic and coherent frequency distribution when Fourier Transformed

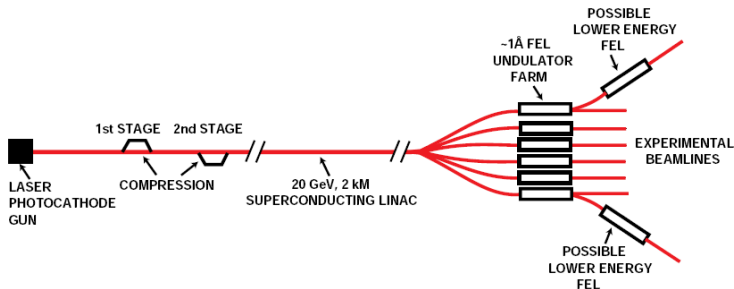
FEL performance



FEL layout

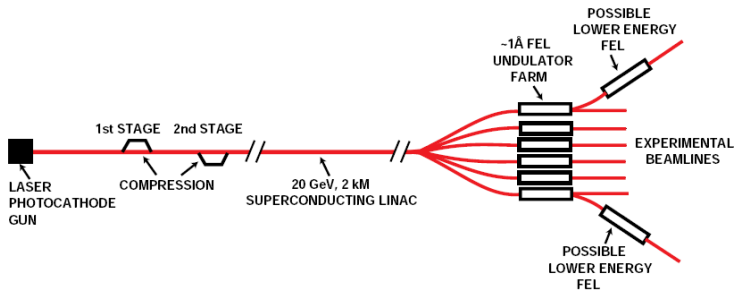


FEL layout



An FEL has a single accelerator whose electron beam is shunted sequentially through different undulators and end stations

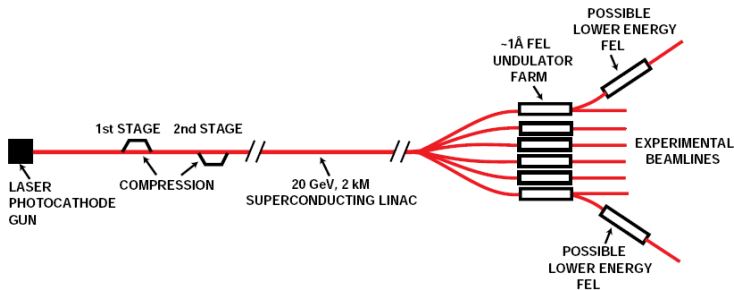
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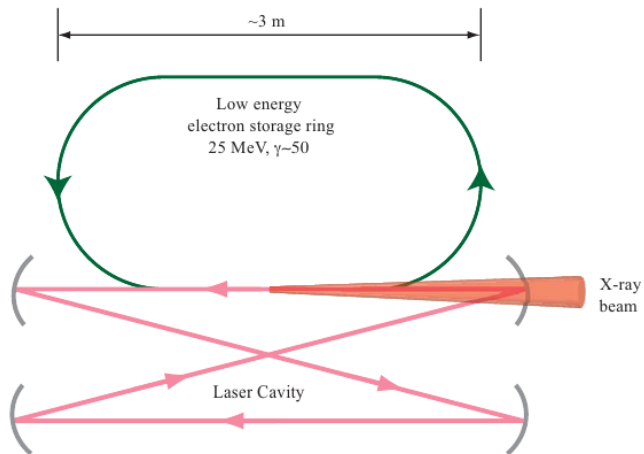


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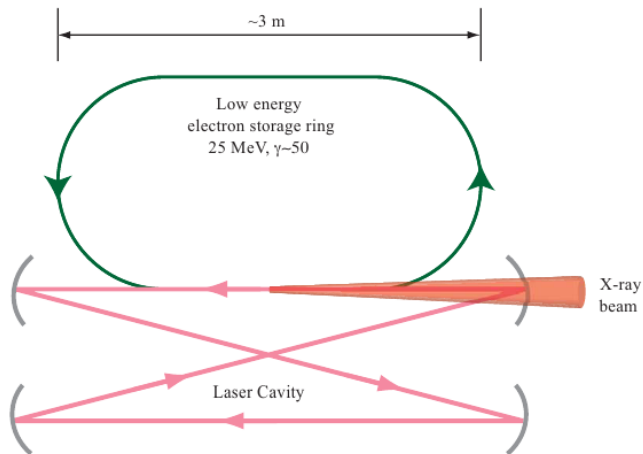
The high brightness usually results in destruction of the sample during the illumination, thus the need for multiple samples and multiple shot experiments

Compact sources



Small low energy, high current electron ring

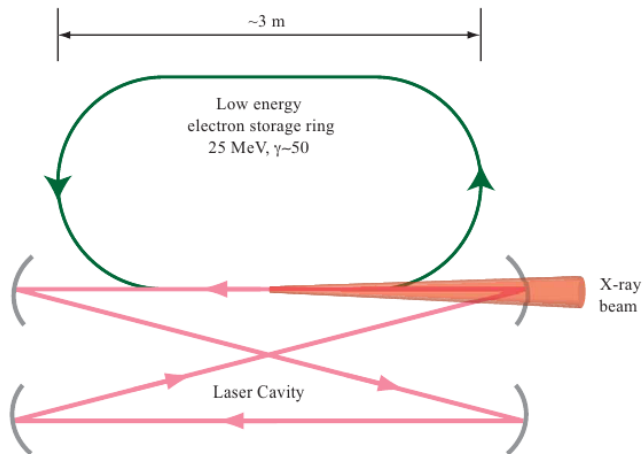
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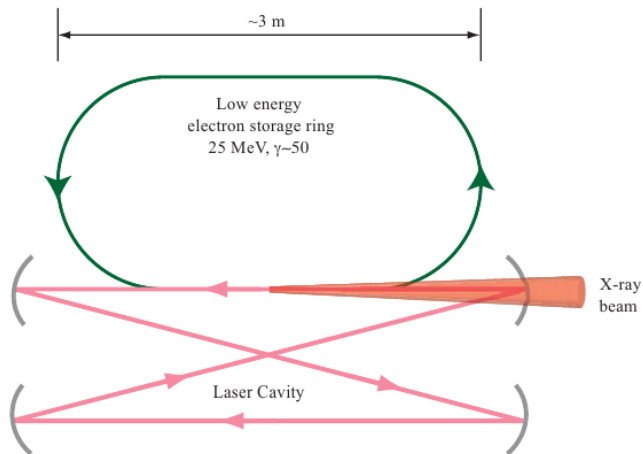


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Undulator is the standing wave of the laser, alternatively can consider this an inverse Compton effect

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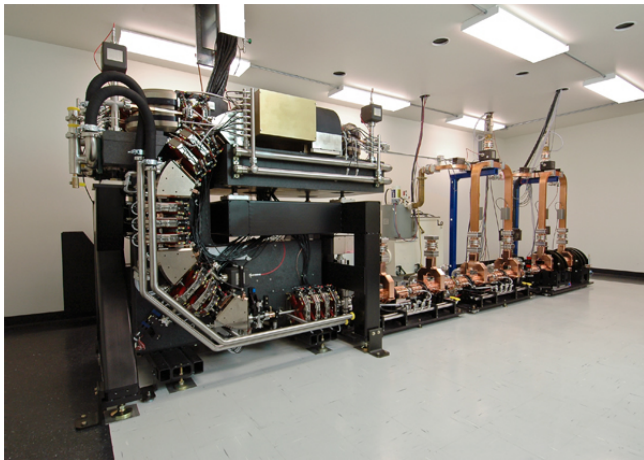
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Cost $\sim$ \$5 M plus $\sim$ \$1 M per year service contract

Types of X-ray Detectors



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Gas detectors

Types of X-ray Detectors



Gas detectors

- Ionization chamber

Types of X-ray Detectors



Gas detectors

- Ionization chamber
- Proportional counter

Types of X-ray Detectors



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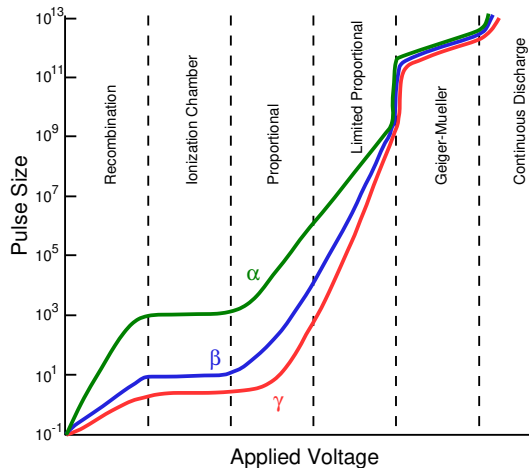
Charge coupled device detectors

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Gas detectors operate in several modes depending on the particle type, gas composition and pressure and voltage applied

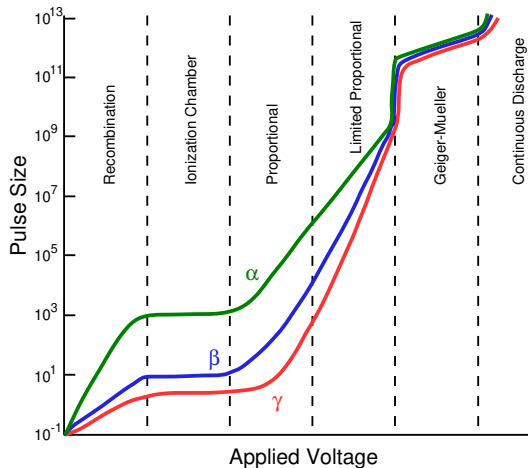


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The most interesting are the ionization, proportional, and Geiger-Mueller



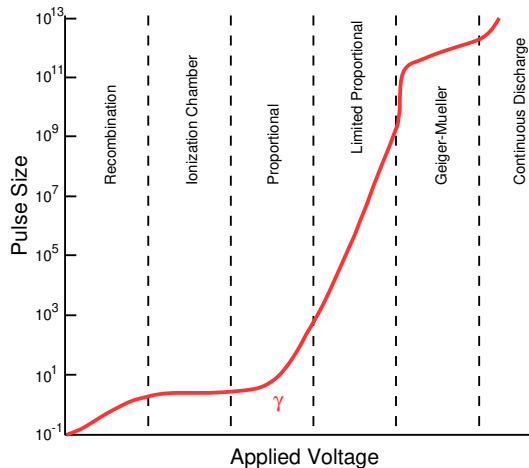
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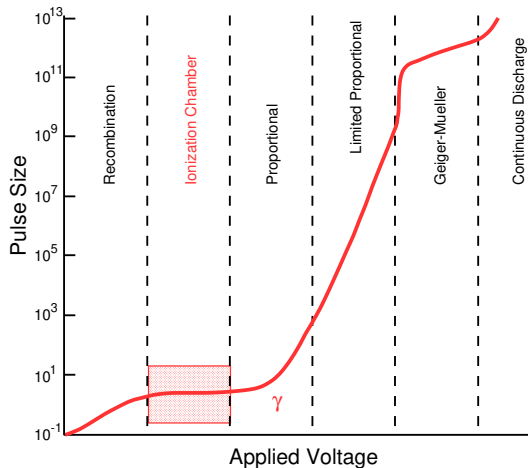


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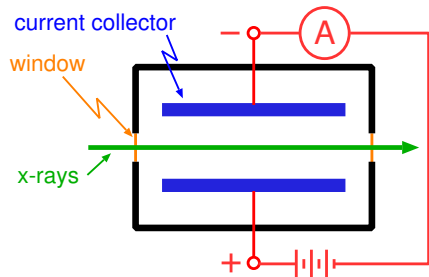
The most useful regime is the ionization region where the output pulse is independent of the applied voltage over a wide range



Ionization Chamber



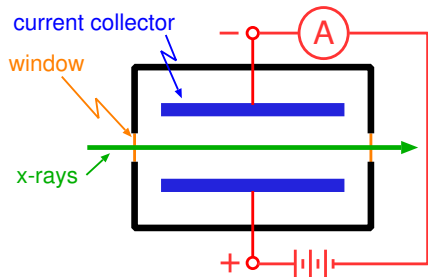
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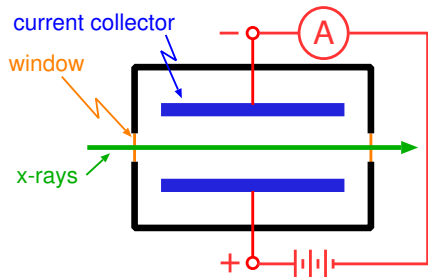
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$$\mu = \sum \rho_i \mu_i$$

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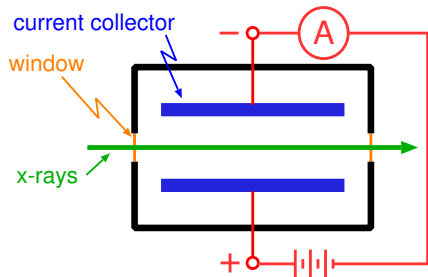
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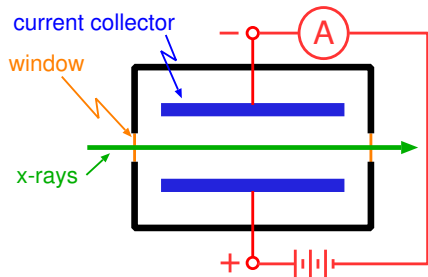
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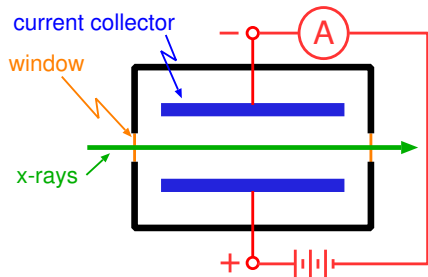
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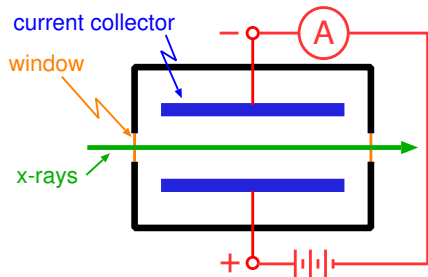
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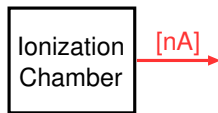
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- 22-41 eV per electron-ion pair (depending on the gas) makes this useful for quantitative measurements.

Getting a reading



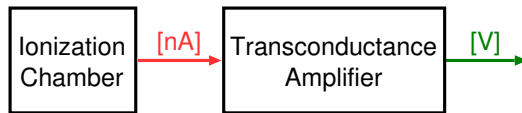
The ionization chamber puts out a **current** in the nA range, this needs to be converted into a useful measurement



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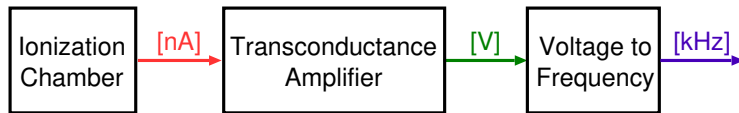


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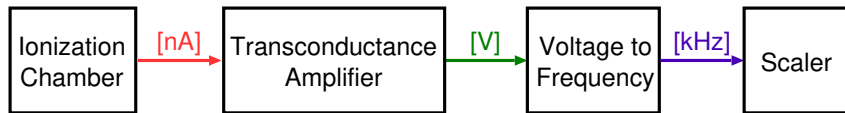
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the digital **pulse train** is counted by a scaler for a user-definable length of time